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With the principle of "Quality Parts, Customers Priority, Honest Operation, and Considerate Service", our business mainly focus on the distribution of electronic components. Line cards we deal with include Microchip, ALPS, ROHM, Xilinx, Pulse, ON, Everlight and Freescale. Main products comprise IC, Modules, Potentiometer, IC Socket, Relay, Connector. Our parts cover such applications as commercial, industrial, and automotives areas.

We are looking forward to setting up business relationship with you and hope to provide you with the best service and solution. Let us make a better world for our industry!



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IRF3704ZPbF
IRF3704ZSPbF
IRF3704ZLPbF
HEXFET® Power MOSFET

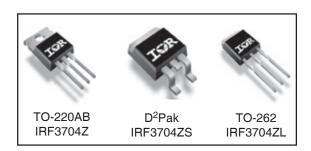
#### **Applications**

- High Frequency Synchronous Buck Converters for Computer Processor Power
- Lead-Free

V <sub>DSS</sub>	R <sub>DS(on)</sub> max	Qg
<b>20V</b>	7.9m $\Omega$	8.7nC

#### **Benefits**

- Low R<sub>DS(on)</sub> at 4.5V V<sub>GS</sub>
- Ultra-Low Gate Impedance
- Fully Characterized Avalanche Voltage and Current



**Absolute Maximum Ratings** 

	Parameter	Max.	Units	
$V_{DS}$	Drain-to-Source Voltage	20	V	
$V_{GS}$	Gate-to-Source Voltage	± 20		
I <sub>D</sub> @ T <sub>C</sub> = 25°C	Continuous Drain Current, V <sub>GS</sub> @ 10V	67 ®	Α	
I <sub>D</sub> @ T <sub>C</sub> = 100°C	Continuous Drain Current, V <sub>GS</sub> @ 10V	47 ©		
I <sub>DM</sub>	Pulsed Drain Current ①	260		
P <sub>D</sub> @T <sub>C</sub> = 25°C	Maximum Power Dissipation	57	W	
P <sub>D</sub> @T <sub>C</sub> = 100°C	Maximum Power Dissipation	28		
	Linear Derating Factor	0.38	W/°C	
$T_J$	Operating Junction and	-55 to + 175	°C	
T <sub>STG</sub>	Storage Temperature Range			
	Soldering Temperature, for 10 seconds	300 (1.6mm from case)		
	Mounting Torque, 6-32 or M3 screw 4	10 lbf•in (1.1N•m)		

#### **Thermal Resistance**

111011114111111111111111111111111111111					
	Parameter	Тур.	Max.	Units	
$R_{\theta JC}$	Junction-to-Case ♡		2.65	°C/W	
$R_{\theta CS}$	Case-to-Sink, Flat Greased Surface @	0.50			
$R_{\theta JA}$	Junction-to-Ambient @ 7		62	1	
$R_{\theta JA}$	Junction-to-Ambient (PCB Mount) ⑤ ⑦		40		

Notes ① through ② are on page 12

### Static @ T<sub>J</sub> = 25°C (unless otherwise specified)

	Parameter	Min.	Тур.	Max.	Units	Conditions
BV <sub>DSS</sub>	Drain-to-Source Breakdown Voltage	20			V	$V_{GS} = 0V, I_D = 250\mu A$
$\Delta \mathrm{BV}_{\mathrm{DSS}}/\Delta \mathrm{T}_{\mathrm{J}}$	Breakdown Voltage Temp. Coefficient		0.014		V/°C	Reference to 25°C, I <sub>D</sub> = 1mA
R <sub>DS(on)</sub>	Static Drain-to-Source On-Resistance	_	6.5	7.9	mΩ	V <sub>GS</sub> = 10V, I <sub>D</sub> = 21A ③
			9.1	11.1	1	V <sub>GS</sub> = 4.5V, I <sub>D</sub> = 17A ③
$V_{GS(th)}$	Gate Threshold Voltage	1.65	2.1	2.55	V	$V_{DS} = V_{GS}$ , $I_D = 250\mu A$
$\Delta V_{GS(th)}/\Delta T_J$	Gate Threshold Voltage Coefficient		-5.6		mV/°C	
I <sub>DSS</sub>	Drain-to-Source Leakage Current			1.0	μΑ	V <sub>DS</sub> = 16V, V <sub>GS</sub> = 0V
				150	1	$V_{DS} = 16V, V_{GS} = 0V, T_{J} = 125^{\circ}C$
$I_{GSS}$	Gate-to-Source Forward Leakage	_		100	nA	V <sub>GS</sub> = 20V
	Gate-to-Source Reverse Leakage			-100		$V_{GS} = -20V$
gfs	Forward Transconductance	48			S	$V_{DS} = 10V, I_{D} = 17A$
$Q_g$	Total Gate Charge	_	8.7	13		
Q <sub>gs1</sub>	Pre-Vth Gate-to-Source Charge		2.9		1	$V_{DS} = 10V$
$Q_{gs2}$	Post-Vth Gate-to-Source Charge		1.1		nC	$V_{GS} = 4.5V$
$Q_gd$	Gate-to-Drain Charge		2.3			I <sub>D</sub> = 17A
$Q_{godr}$	Gate Charge Overdrive		2.4			See Fig. 16
$Q_{sw}$	Switch Charge (Q <sub>gs2</sub> + Q <sub>gd</sub> )		3.4			
Q <sub>oss</sub>	Output Charge		5.6		nC	$V_{DS} = 10V, V_{GS} = 0V$
t <sub>d(on)</sub>	Turn-On Delay Time		8.9			$V_{DD} = 10V, V_{GS} = 4.5V$ ③
t <sub>r</sub>	Rise Time		38			I <sub>D</sub> = 17A
$t_{d(off)}$	Turn-Off Delay Time		11	_	ns	Clamped Inductive Load
t <sub>f</sub>	Fall Time		4.2		]	
C <sub>iss</sub>	Input Capacitance		1220			$V_{GS} = 0V$
C <sub>oss</sub>	Output Capacitance		390		pF	$V_{DS} = 10V$
C <sub>rss</sub>	Reverse Transfer Capacitance		190		]	f = 1.0MHz

### **Avalanche Characteristics**

	Parameter	Тур.	Max.	Units
E <sub>AS</sub>	Single Pulse Avalanche Energy②		36	mJ
I <sub>AR</sub>	Avalanche Current ①		17	Α
E <sub>AR</sub>	Repetitive Avalanche Energy ①		5.7	mJ

#### **Diode Characteristics**

	Parameter	Min.	Тур.	Max.	Units	Conditions
I <sub>S</sub>	Continuous Source Current			67 ®		MOSFET symbol
	(Body Diode)				Α	showing the
I <sub>SM</sub>	Pulsed Source Current			260		integral reverse
	(Body Diode) ①					p-n junction diode.
$V_{SD}$	Diode Forward Voltage			1.0	V	$T_J = 25$ °C, $I_S = 17A$ , $V_{GS} = 0V$ ③
t <sub>rr</sub>	Reverse Recovery Time		11	17	ns	$T_J = 25^{\circ}C, I_F = 17A, V_{DD} = 10V$
Q <sub>rr</sub>	Reverse Recovery Charge		2.3	3.5	nC	di/dt = 100A/μs ③

# International TOR Rectifier

# IRF3704Z/S/LPbF

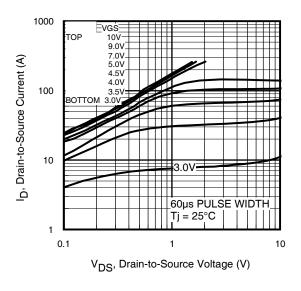


Fig 1. Typical Output Characteristics

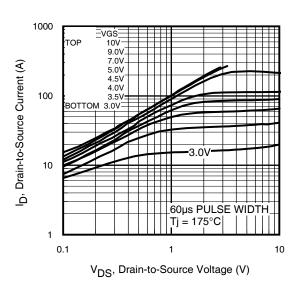


Fig 2. Typical Output Characteristics

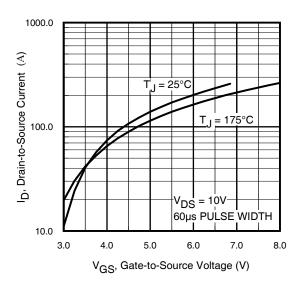
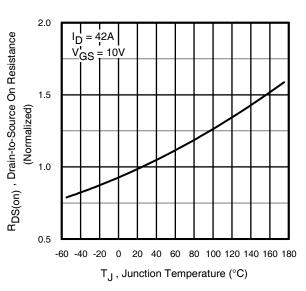
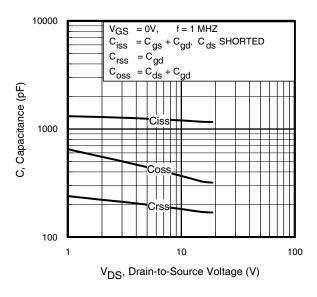


Fig 3. Typical Transfer Characteristics

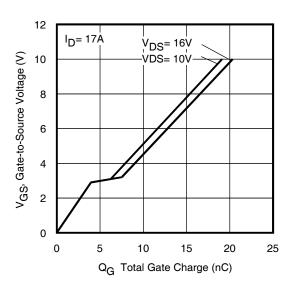


**Fig 4.** Normalized On-Resistance vs. Temperature

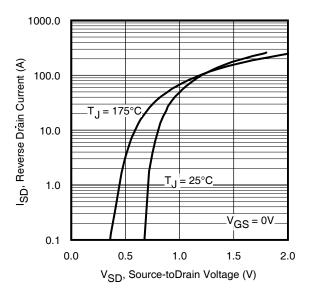
International **IOR** Rectifier



**Fig 5.** Typical Capacitance vs. Drain-to-Source Voltage



**Fig 6.** Typical Gate Charge vs. Gate-to-Source Voltage



**Fig 7.** Typical Source-Drain Diode Forward Voltage

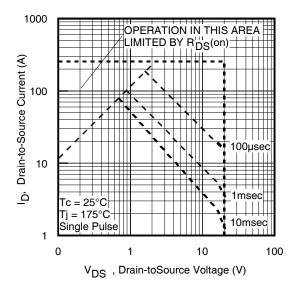
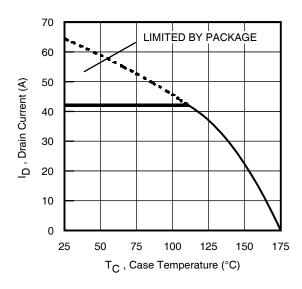
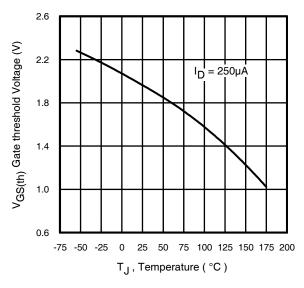


Fig 8. Maximum Safe Operating Area





**Fig 9.** Maximum Drain Current vs. Case Temperature

Fig 10. Threshold Voltage vs. Temperature

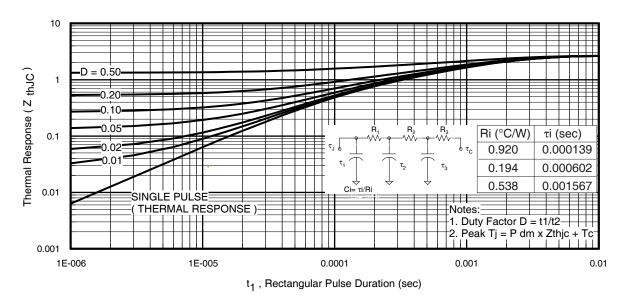


Fig 11. Maximum Effective Transient Thermal Impedance, Junction-to-Case

International **IOR** Rectifier

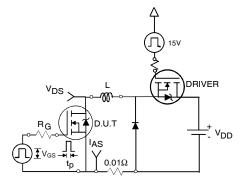


Fig 12a. Unclamped Inductive Test Circuit

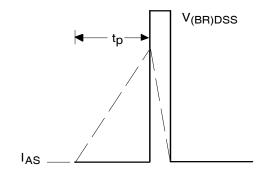


Fig 12b. Unclamped Inductive Waveforms

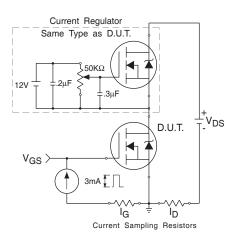
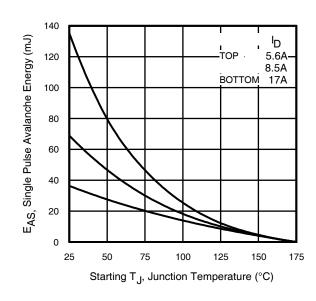


Fig 13. Gate Charge Test Circuit



**Fig 12c.** Maximum Avalanche Energy vs. Drain Current

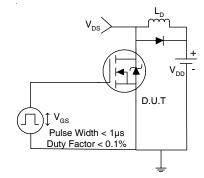


Fig 14a. Switching Time Test Circuit

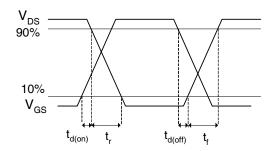


Fig 14b. Switching Time Waveforms

# International TOR Rectifier

# IRF3704Z/S/LPbF

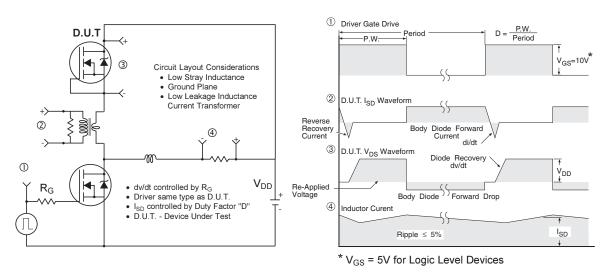


Fig 15. Peak Diode Recovery dv/dt Test Circuit for N-Channel HEXFET® Power MOSFETs

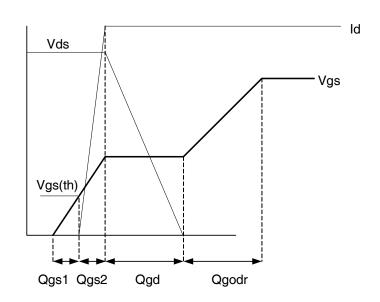


Fig 16. Gate Charge Waveform

#### Power MOSFET Selection for Non-Isolated DC/DC Converters

#### **Control FET**

Special attention has been given to the power losses in the switching elements of the circuit - Q1 and Q2. Power losses in the high side switch Q1, also called the Control FET, are impacted by the  $R_{\rm ds(on)}$  of the MOSFET, but these conduction losses are only about one half of the total losses.

Power losses in the control switch Q1 are given by;

$$P_{loss} = P_{conduction} + P_{switching} + P_{drive} + P_{output}$$

This can be expanded and approximated by;

$$\begin{split} P_{loss} &= \left(I_{rms}^{2} \times R_{ds(on)}\right) \\ &+ \left(I \times \frac{Q_{gd}}{i_{g}} \times V_{in} \times f\right) + \left(I \times \frac{Q_{gs2}}{i_{g}} \times V_{in} \times f\right) \\ &+ \left(Q_{g} \times V_{g} \times f\right) \\ &+ \left(\frac{Q_{oss}}{2} \times V_{in} \times f\right) \end{split}$$

This simplified loss equation includes the terms  $Q_{gs2}$  and  $Q_{oss}$  which are new to Power MOSFET data sheets.

 $Q_{gs2}$  is a sub element of traditional gate-source charge that is included in all MOSFET data sheets. The importance of splitting this gate-source charge into two sub elements,  $Q_{gs1}$  and  $Q_{gs2}$ , can be seen from Fig 16.

 $Q_{gs2}$  indicates the charge that must be supplied by the gate driver between the time that the threshold voltage has been reached and the time the drain current rises to  $I_{dmax}$  at which time the drain voltage begins to change. Minimizing  $Q_{gs2}$  is a critical factor in reducing switching losses in Q1.

 $\rm Q_{\rm oss}$  is the charge that must be supplied to the output capacitance of the MOSFET during every switching cycle. Figure A shows how  $\rm Q_{\rm oss}$  is formed by the parallel combination of the voltage dependant (nonlinear) capacitance's  $\rm C_{\rm ds}$  and  $\rm C_{\rm dg}$  when multiplied by the power supply input buss voltage.

#### Synchronous FET

The power loss equation for Q2 is approximated by:

$$\begin{split} P_{loss} &= P_{conduction} + P_{drive} + P_{output}^* \\ P_{loss} &= \left(I_{rms}^2 \times R_{ds(on)}\right) \\ &+ \left(Q_g \times V_g \times f\right) \\ &+ \left(\frac{Q_{oss}}{2} \times V_{in} \times f\right) + \left(Q_{rr} \times V_{in} \times f\right) \end{split}$$

\*dissipated primarily in Q1.

For the synchronous MOSFET Q2,  $R_{\text{ds(on)}}$  is an important characteristic; however, once again the importance of gate charge must not be overlooked since it impacts three critical areas. Under light load the MOSFET must still be turned on and off by the control IC so the gate drive losses become much more significant. Secondly, the output charge  $Q_{\text{oss}}$  and reverse recovery charge  $Q_{\text{rr}}$  both generate losses that are transfered to Q1 and increase the dissipation in that device. Thirdly, gate charge will impact the MOSFETs' susceptibility to Cdv/dt turn on.

The drain of Q2 is connected to the switching node of the converter and therefore sees transitions between ground and  $V_{\rm in}.$  As Q1 turns on and off there is a rate of change of drain voltage dV/dt which is capacitively coupled to the gate of Q2 and can induce a voltage spike on the gate that is sufficient to turn the MOSFET on, resulting in shoot-through current . The ratio of  $Q_{\rm gd}/Q_{\rm gs1}$  must be minimized to reduce the potential for Cdv/dt turn on.

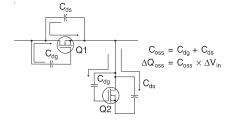
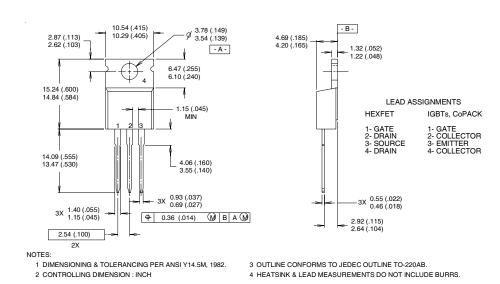


Figure A: Qoss Characteristic

### TO-220AB Package Outline

Dimensions are shown in millimeters (inches)



## TO-220AB Part Marking Information

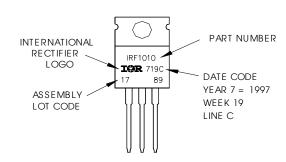
EXAMPLE: THIS IS AN IRF1010

LOT CODE 1789

ASSEMBLED ON WW 19, 1997

IN THE ASSEMBLY LINE "C"

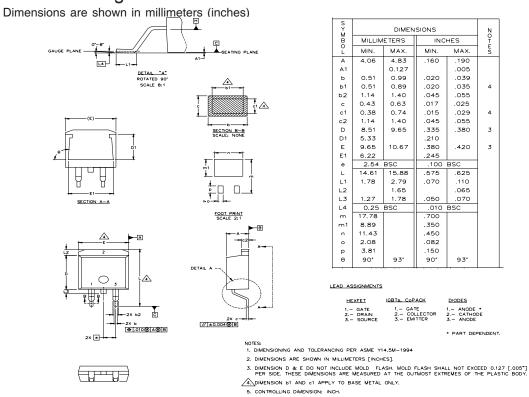
Note: "P" in assembly line position indicates "Lead-Free"



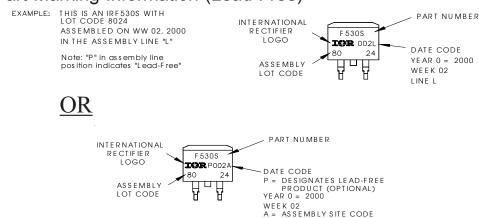
International

TOR Rectifier

### D<sup>2</sup>Pak Package Outline



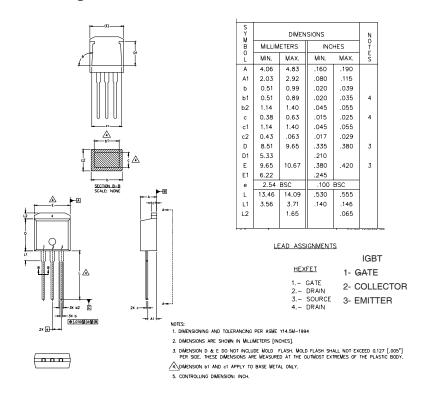
# D<sup>2</sup>Pak Part Marking Information (Lead-Free)



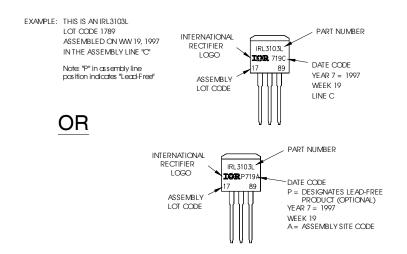
# International IOR Rectifier

## IRF3704Z/S/LPbF

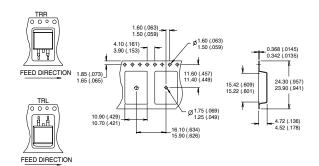
### TO-262 Package Outline

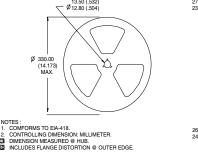


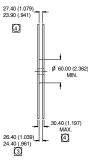
### TO-262 Part Marking Information



### D<sup>2</sup>Pak Tape & Reel Infomation







#### Notes:

- ① Repetitive rating; pulse width limited by max. junction temperature.
- $\label{eq:starting} \begin{tabular}{l} \begin{ta$
- 3 Pulse width  $\leq 400 \mu s$ ; duty cycle  $\leq 2\%$ .
- 4 This is only applied to TO-220AB pakcage.
- ⑤ This is applied to D<sup>2</sup>Pak, when mounted on 1" square PCB (FR-4 or G-10 Material). For recommended footprint and soldering techniques refer to application note #AN-994.
- © Calculated continuous current based on maximum allowable junction temperature. Package limitation current is 42A.
- ⑦ R<sub>θ</sub> is measured at T<sub>J</sub> approximately 90°C

#### TO-220AB package is not recommended for Surface Mount Application.

Data and specifications subject to change without notice. This product has been designed and qualified for the Industrial market.

Qualification Standards can be found on IR's Web site.



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Note: For the most current drawings please refer to the IR website at: <a href="http://www.irf.com/package/">http://www.irf.com/package/</a>